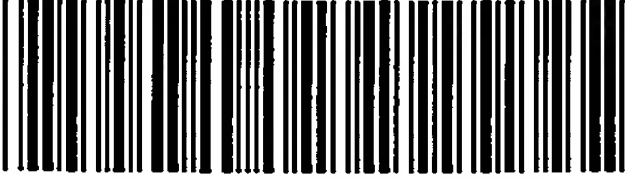


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/621,881	LEE ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Tai Duong	2871	

SEARCHED			
Class	Subclass	Date	Examiner
349	43	5/30/2006	TD
	110		
	111		
	123		
	132		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (US PGPUB, USPAT, EPO, JPO, DERWENT, IBM TDB) see search history printout	5/30/2006, 8/1/2006	TD